PCN Number:20231016006.1PCN Date:October 17, 202Title:Qualification of RFAB using qualified Process Technology, Die Revision and Assembly/BOM options for select devicesCustomer Contact:Change Management teamDept:Quality ServiceProposed 1st Ship Date:Jan 16, 2024Estimated Sample Availability:Nov 16, 2023**Sample requests received after November 16, 2023 will not be supported.						
Assembly/BOM options for select devices Customer Contact: Change Management team Dept: Quality Service Proposed 1 st Ship Date: Jan 16, 2024 Estimated Sample Availability: *Sample requests received after November 16, 2023 will not be supported.						
Proposed 1 st Ship Date: Jan 16, 2024 Estimated Sample Availability: Nov 16, 2023* *Sample requests received after November 16, 2023 will not be supported.	5					
*Sample requests received after November 16, 2023 will not be supported.						
Change Type:						
□ Assembly Site						
Assembly Process Data Sheet Wafer Bump Process						
Assembly Materials Part number change Wafer Fab Site						
☐ Mechanical Specification ☐ Test Site ☐ Wafer Fab Materials						
☐ Packing/Shipping/Labeling ☐ Test Process ☐ Wafer Fab Process						
PCN Details						
Description of Change:						
Texas Instruments is pleased to announce the addition of RFAB using the TIB qualified proce	 SS					
technology and additional Assembly/BOM options for the devices listed below.						
, , , , , , , , , , , , , , , , , , ,						
Current Fab Site Additional Fab Site						
Current Fab Process Wafer Additional Process Wafer						
Site Diameter Fab Site Diamet	er					
SFAB JI1 150 mm RFAB TIB 300 mr	n					
The die was also changed as a result of the process change.						
Additional BOM items are as follows:						
Additional BOM Items are as follows.						
Group 1 BOM Table (RFAB/Process migration & BOM Option):						
Current Additional]					
Bond wire Composition, diameter Au, 0.8 or Cu, 0.96 or 1.0 mil Cu, 0.8mil						
Group 2 BOM Table (RFAB/Process migration/BOM Option plus TI Malaysia as addit	ional					
Assembly site): TI Mexico TI Malaysia	1					
•						
Bond wire Composition, diameter Cu, 1.0 mil Cu, 0.8 mil	ļ					
Group 3 BOM Table (RFAB/Process migration/BOM Option plus TI Malaysia as addit	ional					
Assembly site):						
TI Taiwan TI Malaysia						
Bond wire Composition, diameter Au, 0.96 mil Cu, 0.8mil						
Qual details are provided in the Qual Data Section.						
Reason for Change:						
-						
These changes are part of our multiyear plan to transition products from our 150-millimeter						
-	ır					

None

Impact on Environmental Ratings:

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
⊠ No Change	⊠ No Change	⊠ No Change	⊠ No Change

Changes to product identification resulting from this PCN:

Fab Site Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City	
SH-BIP-1	SHE	USA	Sherman	
RFAB	RFB	USA	Richardson	

Die Rev:

Current **New**

Die Rev [2P]	Die Rev [2P]
Α	A

Assembly Site Information:

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City	
TI Mexico	MEX	MEX	Aguascalientes	
TI Taiwan	TAI	TWN	Chung Ho, New Taipei City	
TI Malaysia	MLA	MYS	Kuala Lumpur	

Sample product shipping label (not actual product label)



(L)T0:1750



(1P) SN74LS07NSR 31T)LOT: 3959047MLA 4W) TKY(1T) 7523483SI2 (2P) REV: (20L) CSO: SHE (22L) ASO: MLA 21L) CCO:USA

(23L) ACO: MYS

Product Affected:

Group 1 Device list (RFAB/Process migration & BOM Option):

LM2901DR LM3302DR LM339DR

Group 2 Device list (RFAB/Process migration/BOM Option plus TI Malaysia as additional **Assembly site):**

LM2901VQDR

Group 3 Device list (RFAB/Process migration/BOM Option plus TI Malaysia as additional **Assembly site):**

LM139DR LM139DRG4

For alternate parts with similar or improved performance, please visit the product page on TI.com

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: LM2901VQDR	QBS Reference: SN74HCS74QDRQ1	QBS Reference: LM324BIPWR	QBS Reference: LM2901BQDRQ1	QBS Reference: MC33063ADR	QBS Reference: LM2901BQPWRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	1/77/0	3/231/0	-
UHAST	А3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	-	1/77/0	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	1/77/0	3/231/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	3/231/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	1/77/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	-	2/154/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	1/77/0	-	1/77/0
ESD	E2	ESD CDM	-	500 Volts	1/3/0	-	-	1/3/0	-	-
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	-	1/6/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	1/30/0	-	-	1/30/0	-	3/90/0

- QBS: Qual By Similarity
- Qual Device LM2901VQDR is qualified at MSL1 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2308-054

[1]-Unit damaged prior to ATE Package cracked down the middle

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

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